

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BZX384-B4V7-Q						
								Part Description
		Nexperia DHAM Zener						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
			TEST					
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours			_		
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, VR = 80 % of rated reverse						
# B1	Bias	voltage	1000 hours	250	11400	0		
		MIL-STD-750-1						
		M1038 Method B						
	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet						
# B1b	Steady State Operational	reverse current	1000 hours	44	1920	0		
	TC	JESD22-A104				_		
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0		
	UHACT	JECD22 A110						
# A3 or	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %						
# A3 01	Offblased FIAST		- 96 hours	311	14080	0		
		JESD22-A102						
	AC Autoplaye	Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
	HOTOD	JESD22-A101						
	H3TRB	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	High Humidity High	rated reverse voltage ^[1]	1000 have-	211	14000	0		
# A2 alt	Temperature Reverse Bias		1000 hours	311	14080	0		
	701	MIL-STD-750 Method 1037						
" ^ -	IOL	ton = toff, devices powered to insure ΔTj =	1000 5	212	14120	0		
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	312	14120	0		
	RSH	JECD22 A111						
# C0	RSH Resistance to Solder Heat	JESD22-A111	10.0	260	0070	0		
# C8		200 C ± J C	10 s	269	8070	0		
# C10	SD Solderability	J-STD-002		10	6660	0		
# C10	Solderability	J-31D-002		19	6660	0		

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11400	0	0,37	2,68E+09

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